

(11)

## PATENT ABSTRACTS OF JAPAN

(11)Publication number : 11-326203  
 (43)Date of publication of application : 26.11.1999

(51)Int.Cl. G01N 21/59  
 G01N 21/49

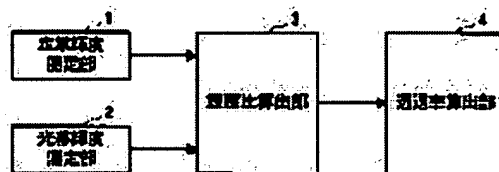
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## (54) TRANSMITTANCE MEASURING METHOD

## (57)Abstract:

PROBLEM TO BE SOLVED: To provide a transmittance measuring method which can reduce transmittance measuring errors and, at the same time, can reduce the workload when instruments are installed and maintained.

SOLUTION: In a transmittance measuring method, the transmittance of a gas in a space is measured in such a way that the steady luminance in the space which is not affected by the fluctuation of the transmittance is measured by means of a steady-luminance measuring section 1 and the veiling luminance in the space which fluctuates in accordance with the fluctuation of transmittance is measured by means of a veiling luminance measuring section 2. Then the luminance ratio between the luminance measured by means of the measuring section 1 and that measured by means of the measuring section 2 is calculated by means of a luminance ratio calculating section 3 and the transmittance of the gas in the space is calculated by means of a transmittance calculating section 4 based on the luminance ratio.



## LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

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[Date of requesting appeal against examiner's  
decision of rejection]

[Date of extinction of right]

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